

Application No.	Applicant(s)	
10/813,869	LEE ET AL.	
Examiner	Art Unit	
Yuwen Pan	2682	

SEARCHED				
Class	Subclass	Date	Examiner	
455	41.2 502 574	1/10/05	yw	
	342. 2		1	
	552.			
	553.1			
	426.1			
	41.3			
370	350			
	503			
	504			
	411			
	500			
	515	1	7	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
415	41.2	1/20/05	Yw	
	343.1		1	
	343.2		V	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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